

Composing graph theory and deep neural networks to evaluate SEU type soft error effects

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Enabling cross-layer reliability and functional safety assessment through ML-based compact models

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Gate-level graph representation learning : a step towards the improved stuck-at faults analysis

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Machine learning clustering techniques for selective mitigation of critical design features

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Machine learning to tackle the challenges of transient and soft errors in complex circuits

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On antagonism between side-channel security and soft-error reliability in BNN inference engines

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Tau lepton identification and reconstruction : a new frontier for jet-tagging ML algorithms

Lange, Thomas; Nandan, Saswati; Pata, Joosep; **Tani, Laurits;** Veelken, Christian Computer physics communications 2024 / art. 109095 <https://doi.org/10.1016/j.cpc.2024.109095>

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Understanding multidimensional verification : where functional meets non-functional

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